



YJQ50G04H

N-Channel Enhancement Mode Field Effect Transistor

Product Summary

V_{DS}	40V
I_D	50A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	7m
100% EAS Tested	

General Description

Split gate MOSFET Assembly
Excellent package for heat dissipation
High density cell design for low $R_{DS(ON)}$
Moisture Sensitivity Level 1
Epoxy Meets UL 94 V-0 Flammability Rating
Halogen Free

AppliQR6)JTJETQ EMC 84.2eW*nBT00888 0 3(s 5





Typical Electrical and Thermal Characteristics Diagrams

Figure 1. Output Characteristics

Figure 2. Transfer Characteristics

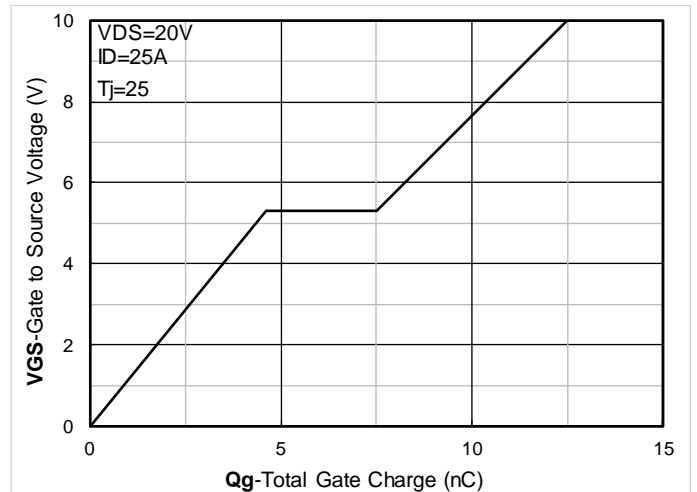
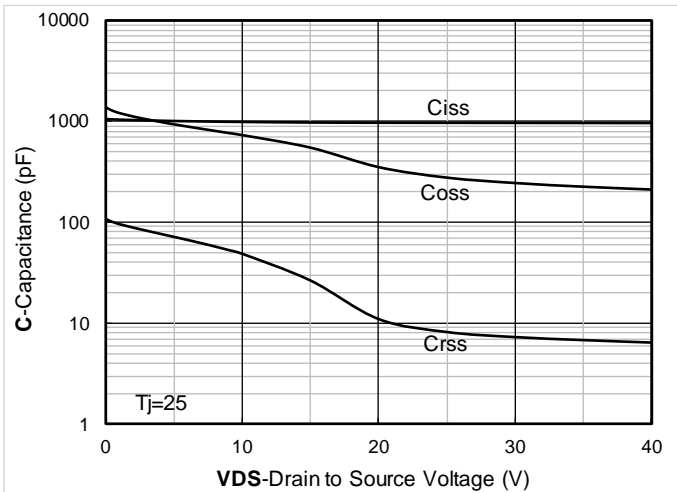


Figure 3. Capacitance Characteristics

Figure 4. Gate Charge

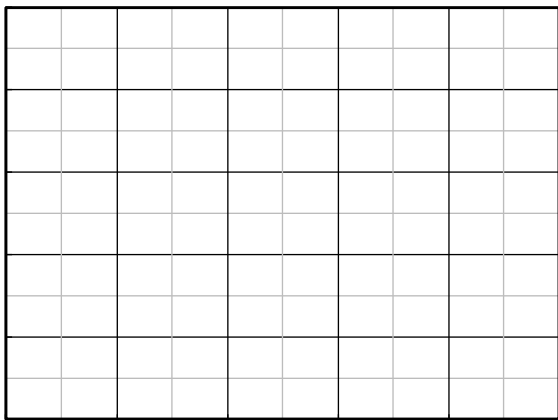


Figure 5. On-Resistance vs Gate to Source Voltage

Figure 6. Normalized On-Resistance



YJQ50G04H

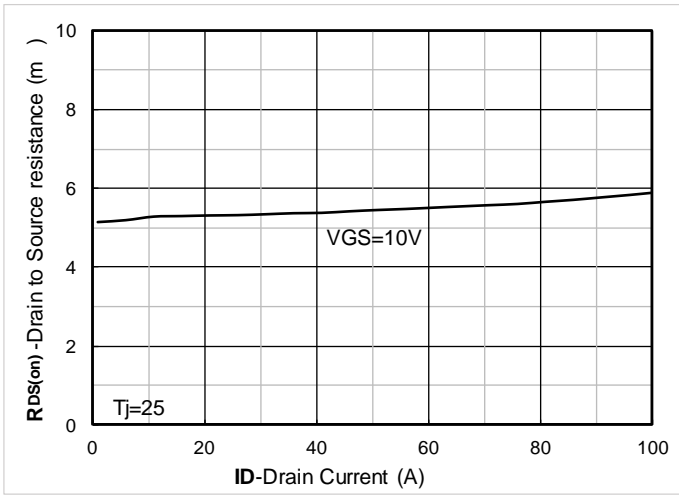


Figure 7. $R_{DS(on)}$ VS Drain Current

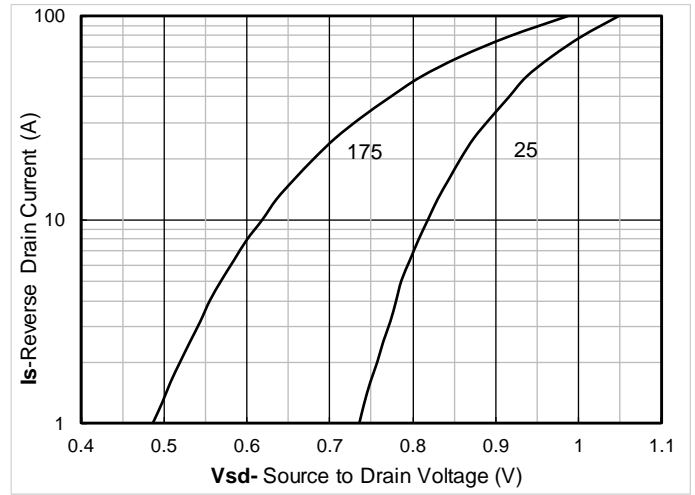


Figure 8. Forward characteristics of reverse diode

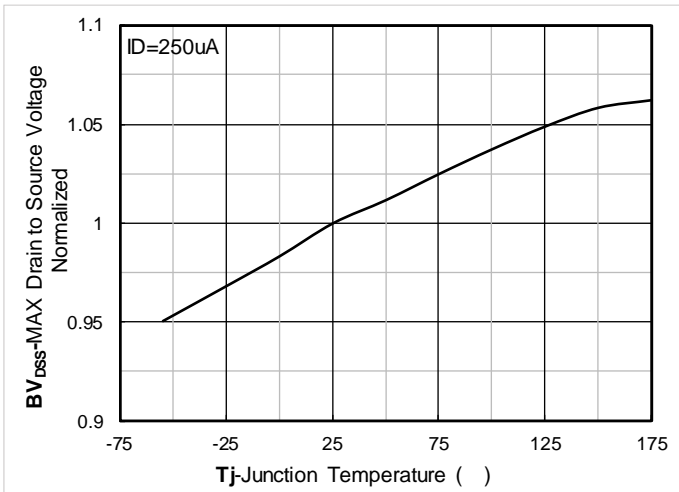


Figure 9. Normalized breakdown voltage

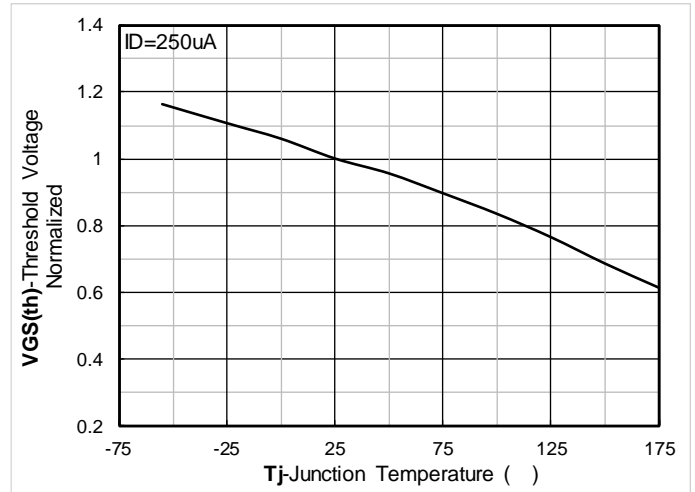


Figure 10. Normalized Threshold voltage

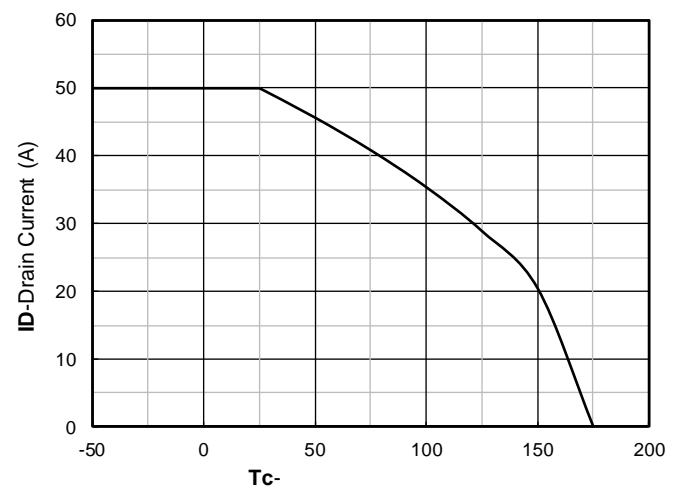


Figure 11. Current dissipation

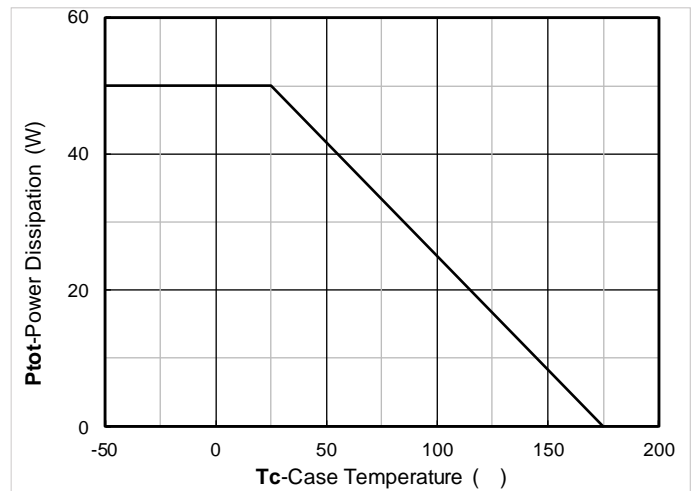
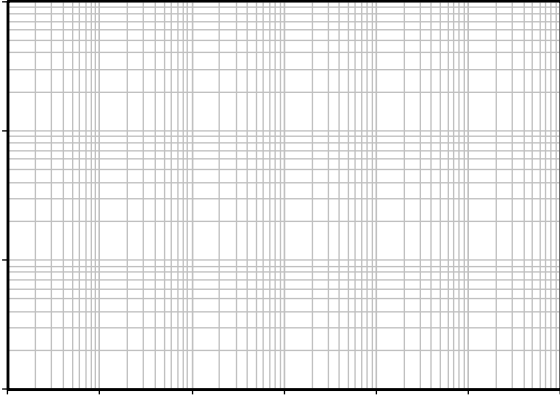


Figure 12. Power dissipation





YJQ50G04H

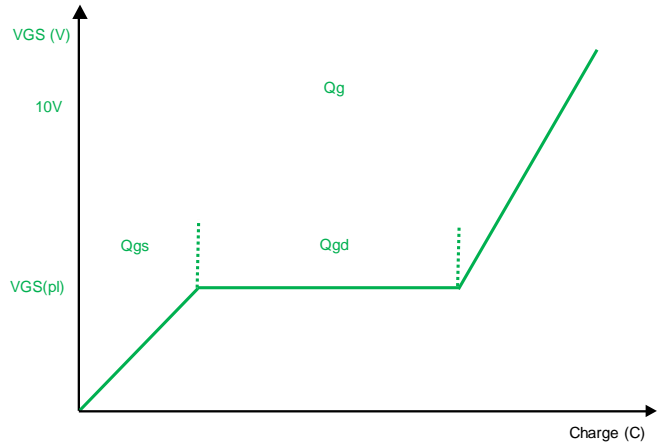
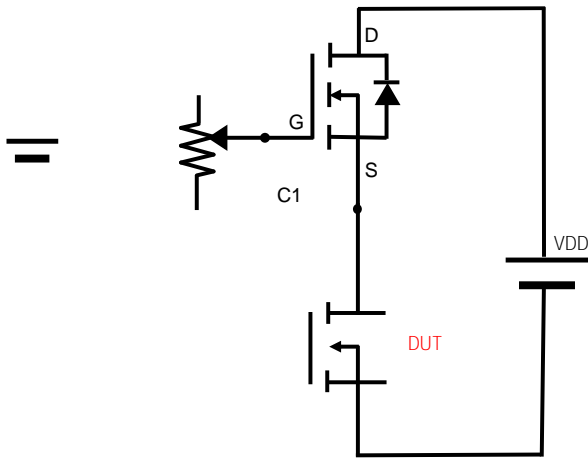


Figure B. Gate Charge Test Circuit & Waveform

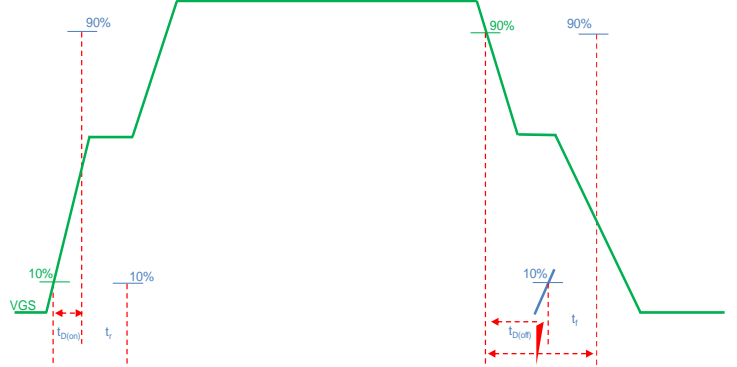


Figure C. Resistive Switching Test Circuit & Waveform

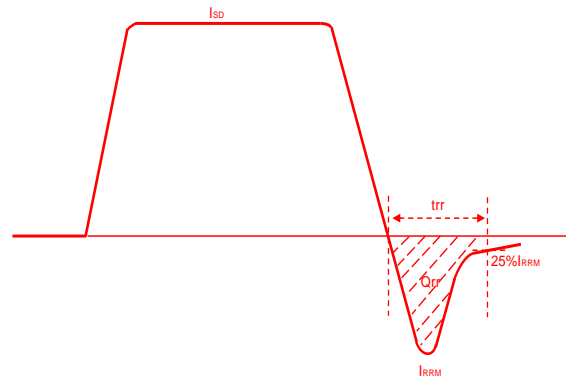
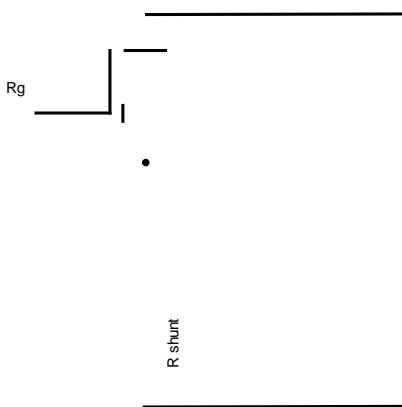
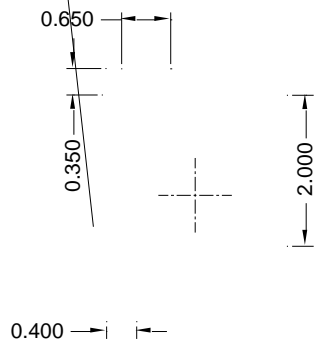
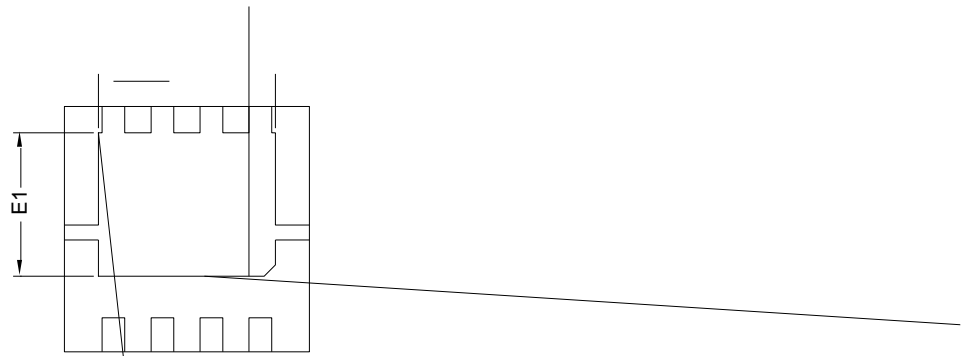


Figure D. Diode Recovery Test Circuit & Waveform



YJQ50G04H

DFN3333-8L-A-0.8MM Package information



- Note:
1. Controlling dimension: in millimeters.
 2. General tolerance: ± 0.10 mm.
 3. The pad layout is for reference purposes only.

Suggested Solder Pad Layout
Top View



YJQ50G04H

Disclaimer